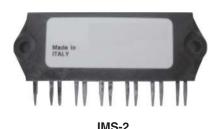
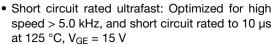


# IGBT SIP Module (Short Circuit Rated Ultrafast IGBT)



PRODUCT SUMMARY					
OUTPUT CURRENT IN A TYPICAL 20 kHz MOTOR DRIVE					
$I_{RMS}$ per phase (3.1 kW total) with $T_C = 90$ °C	11 A <sub>RMS</sub>				
TJ	125 °C				
Supply voltage	360 V <sub>DC</sub>				
Power factor	0.8				
Modulation depth (see fig. 1)	115 %				
V <sub>CE(on)</sub> (typical) at I <sub>C</sub> = 13 A, 25 °C	1.8 V				
Package	SIP				
Circuit	Three Phase Inverter				

#### **FEATURES**





ROHS COMPLIAN

- Fully isolated printed circuit board mount package
- Switching-loss rating includes all "tail" losses
- HEXFRED® soft ultrafast diodes
- UL approved file E78996
- Designed and qualified for industrial level
- Material categorization: For definitions of compliance please see www.vishay.com/doc?99912

#### **DESCRIPTION**

The IGBT technology is the key to Vishay's Semiconductors advanced line of IMS (Insulated Metal Substrate) power modules. These modules are more efficient than comparable bipolar transistor modules, while at the same time having the simpler gate-drive requirements of the familiar power MOSFET. This superior technology has now been coupled to a state of the art materials system that maximizes power throughput with low thermal resistance. This package is highly suited to motor drive applications and where space is at a premium.

ABSOLUTE MAXIMUM RATINGS						
PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS		
Collector to emitter voltage	V <sub>CES</sub>		600	V		
		T <sub>C</sub> = 25 °C	24			
Continuous collector current	I <sub>C</sub>	T <sub>C</sub> = 100 °C	13			
Pulsed collector current	I <sub>CM</sub> <sup>(1)</sup>		48	Α		
Clamped inductive load current	I <sub>LM</sub> <sup>(2)</sup>		48			
Short circuit withstand time	t <sub>SC</sub>	T <sub>C</sub> = 100 °C	9.3	μs		
Gate to emitter voltage	V <sub>GE</sub>		± 20	V		
Isolation voltage	V <sub>ISOL</sub>	t = 1 min, any terminal to case	2500	V <sub>RMS</sub>		
Maximum power dissipation, each IGBT	P <sub>D</sub>	T <sub>C</sub> = 25 °C	63	W		
		T <sub>C</sub> = 100 °C	25			
Operating junction and storage temperature range	T <sub>J</sub> , T <sub>Stg</sub>		- 55 to + 150	00		
Soldering temperature		For 10 s, (0.063" (1.6 mm) from case)	300	°C		
Mounting torque		6-32 or M3 screw 5 to 7 (0.55 to 0.		lbf ⋅ in (N ⋅ m)		

#### Notes

<sup>(1)</sup> Repetitive rating;  $V_{GE} = 20 \text{ V}$ , pulse width limited by maximum junction temperature (see fig. 20)

 $<sup>^{(2)}</sup>$   $V_{CC}$  = 80 % (V<sub>CES</sub>),  $V_{GE}$  = 20 V, L = 10  $\mu H,\,R_{G}$  = 10  $\Omega$  (see fig. 19)





THERMAL AND MECHANICAL SPECIFICATIONS					
PARAMETER	SYMBOL	TYP.	MAX.	UNITS	
Junction to case, each IGBT, one IGBT in conduction	R <sub>thJC</sub> (IGBT)	-	2.2		
Junction to case, each DIODE, one DIODE in conduction	R <sub>thJC</sub> (DIODE)	-	3.7	°C/W	
Case to sink, flat, greased surface	R <sub>thCS</sub> (MODULE)	0.10	-		
Weight of module		20	-	g	
Weight of module		0.7	-	oz.	

<b>ELECTRICAL SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C unless otherwise specified)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNITS
Collector to emitter breakdown voltage	V <sub>(BR)CES</sub> (1)	$V_{GE} = 0 \text{ V}, I_{C} = 250 \mu\text{A}$	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 250 μA		-	-	٧
Temperature coeff. of breakdown voltage	$\Delta V_{(BR)CES}/\Delta T_J$	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1.0 mA	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1.0 mA		0.63	-	V/°C
		I <sub>C</sub> = 13 A		-	1.80	2.3	V
Collector to emitter saturation voltage V <sub>CE(on)</sub>	V <sub>CE(on)</sub>	I <sub>C</sub> = 24 A	$V_{GE} = 15 \text{ V}$ See fig. 2, 5	-	1.80	=	
		I <sub>C</sub> = 13 A, T <sub>J</sub> = 150 °C	<b>3</b> ,	-	1.56	1.73	
Gate threshold voltage	V <sub>GE(th)</sub>	V V I 050 ·· A		3.0	-	6.0	
Temperature coeff. of threshold voltage	$\Delta V_{GE(th)}/\Delta T_{J}$	$V_{CE} = V_{GE}$ , $I_C = 250 \mu A$		-	- 13	-	mV/°C
Forward transconductance	g <sub>fe</sub> <sup>(2)</sup>	V <sub>CE</sub> = 100 V, I <sub>C</sub> = 10 A		11	18	-	S
		$V_{GE} = 0 \text{ V}, V_{CE} = 600 \text{ V}$		-	-	250	
Zero gate voltage collector current	gate voltage collector current I <sub>CES</sub>		V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V, T <sub>J</sub> = 150 °C		-	3500	μA
Diede ferende allere der	I <sub>C</sub> = 15 A	O fir 10	-	1.3	1.7	V	
Diode forward voltage drop	Diode forward voltage drop V <sub>FM</sub>	I <sub>C</sub> = 15 A, T <sub>J</sub> = 150 °C	See fig. 13	-	1.2	1.6	V
Gate to emitter leakage current	I <sub>GES</sub>	V <sub>GE</sub> = ± 20 V		-	-	± 100	nA

#### Notes

 $<sup>^{(1)}~</sup>$  Pulse width  $\leq 80~\mu s,~duty~factor \leq 0.1~\%$ 

 $<sup>^{(2)}</sup>$  Pulse width 5.0  $\mu$ s; single shot





PARAMETER	SYMBOL	,	TEST CONDI	TIONS	MIN.	TYP.	MAX.	UNITS																
Total gate charge (turn-on)	Qg	$I_C = 13 \text{ A}$ $V_{CC} = 400 \text{ V}$ $V_{GE} = 15 \text{ V}$ See fig. 8			-	110	170	nC																
Gate to emitter charge (turn-on)	Q <sub>ge</sub>				-	14	21																	
Gate to collector charge (turn-on)	Q <sub>gc</sub>				-	49	74																	
Turn-on delay time	t <sub>d(on)</sub>				-	50	-																	
Rise time	t <sub>r</sub>	T <sub>J</sub> = 25 °C				30	-	no																
Turn-off delay time	t <sub>d(off)</sub>	$I_C = 13 \text{ A}, V_C$			-	110	170	ns																
Fall time	t <sub>f</sub>	V <sub>GE</sub> = 15 V,	$R_G$ = 10 $\Omega$ es include "tail	" and diode	-	91	140																	
Turn-on switching loss	E <sub>on</sub>	reverse reco		and diode	-	0.56	-																	
Turn-off switching loss	E <sub>off</sub>	See fig. 9, 1	See fig. 9, 10, 18				-	mJ																
Total switching loss	E <sub>ts</sub>						1.1																	
Short circuit withstand time	t <sub>sc</sub>	V <sub>CC</sub> = 360 V,T <sub>J</sub> = 125 °C V <sub>GE</sub> = 15 V, R <sub>G</sub> = 10 Ω, V <sub>CPK</sub> < 500 V			10	-	-	μs																
Turn-on delay time	t <sub>d(on)</sub>		-	47	-																			
Rise time	t <sub>r</sub>		T <sub>J</sub> = 150 °C, see fig. 9, 10, 11, 18 I <sub>C</sub> = 13 A, V <sub>CC</sub> = 480 V			30	-	ns																
Turn-off delay time	t <sub>d(off)</sub>	$V_{GE}$ = 15 V, $R_{G}$ = 10 $\Omega$ Energy losses include "tail" and			-	250	-																	
Fall time	t <sub>f</sub>				-	150	-																	
Total switching loss	E <sub>ts</sub>	- diode revers	diode reverse recovery  Measured 5 mm from package			1.28	-	mJ																
Internal emitter inductance	L <sub>E</sub>	Measured 5				7.5	-	nH																
Input capacitance	C <sub>ies</sub>	V <sub>GE</sub> = 0 V		-	1600	-																		
Output capacitance	C <sub>oes</sub>	$V_{CC} = 30 \text{ V}$ f = 1.0  MHz	V <sub>CC</sub> = 30 V		-	130	-	рF																
Reverse transfer capacitance	C <sub>res</sub>	See fig. 7	•		-	55	-	1																
		T <sub>J</sub> = 25 °C			-	42	60																	
Diode reverse recovery time	t <sub>rr</sub>	T <sub>J</sub> = 125 °C	See fig. 14		-	74	120	ns																
5		T <sub>J</sub> = 25 °C Se	See fig. 15		-	4.0	6.0																	
Diode peak reverse recovery charge	I <sub>rr</sub>			I <sub>F</sub> = 15 A	-	6.5	10	A																
		$T_{J} = 25 ^{\circ}\text{C}$ $T_{J} = 125 ^{\circ}\text{C}$ See fig. 16	25 °C	V <sub>R</sub> = 200 V dI/dt = 200 A/μs	-	80	180																	
Diode reverse recovery charge	$Q_{rr}$		See rig. 16	-	220	600	nC																	
Diode peak rate of fall of recovery		T <sub>J</sub> = 25 °C							<b>.</b>	<b>.</b>											-	188	-	.,
dl/rec/M/dt	T <sub>J</sub> = 125 °C	See fig. 17		-	160	-	- A/μs																	

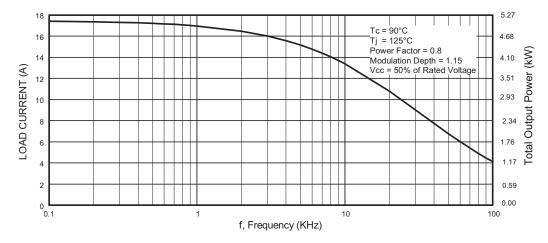


Fig. 1 - Typical Load Current vs. Frequency (Load Current = I<sub>RMS</sub> of Fundamental)

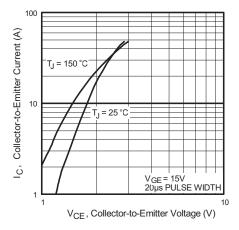


Fig. 2 - Typical Output Characteristics

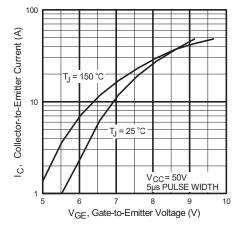


Fig. 3 - Typical Output Characteristics

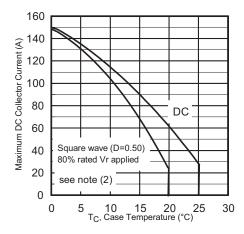


Fig. 4 - Maximum Collector Current vs. Case Temperature

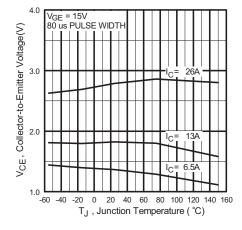


Fig. 5 - Typical Collector to Emitter Voltage vs. Junction Temperature



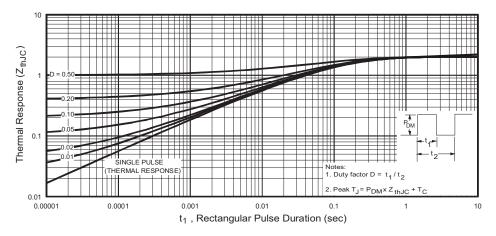


Fig. 6 - Maximum IGBT Effective Transient Thermal Impedance, Junction to Case

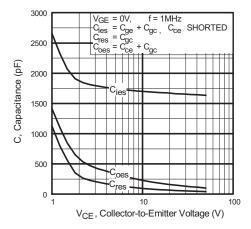


Fig. 7 - Typical Capacitance vs. Collector to Emitter Voltage

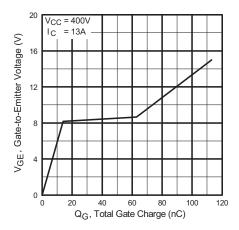


Fig. 8 - Typical Gate Charge vs. Gate to Emitter Voltage

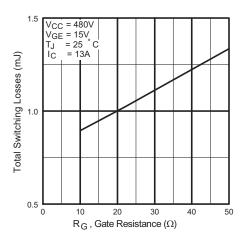


Fig. 9 - Typical Switching Losses vs. Gate Resistance

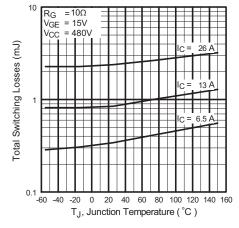


Fig. 10 - Typical Switching Losses vs. Junction Temperature



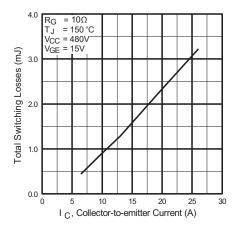


Fig. 11 - Typical Switching Losses vs. Collector to Emitter Current

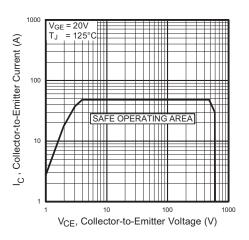


Fig. 12 - Turn-Off SOA

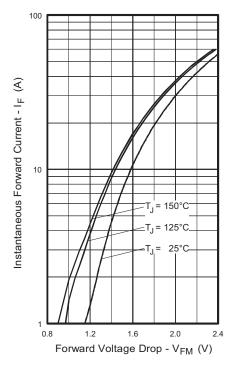


Fig. 13 - Maximum Forward Voltage Drop vs. Instantaneous Forward Current



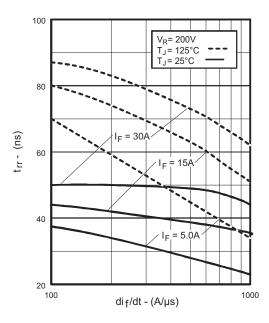


Fig. 14 - Typical Reverse Recovery Time vs. dl<sub>F</sub>/dt

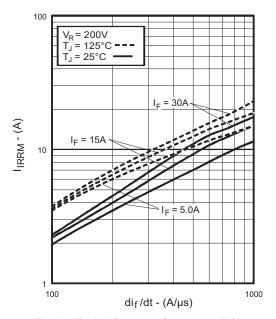


Fig. 15 - Typical Recovery Current vs. dl<sub>F</sub>/dt

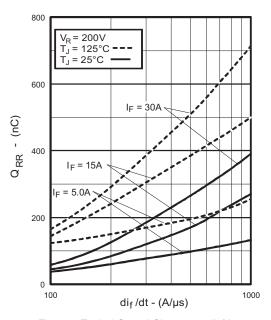


Fig. 16 - Typical Stored Charge vs. dl<sub>F</sub>/dt

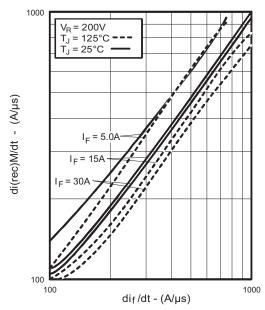


Fig. 17 - Typical  $dI_{(rec)M}/dt$  vs  $dI_F/dt$ 



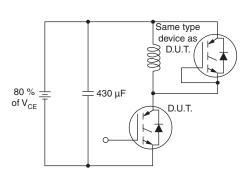


Fig. 18a - Test Circuit for Measurement of  $I_{LM}$ ,  $E_{on}$ ,  $E_{off(diode)}$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$ ,  $t_{d(on)}$ ,  $t_r$ ,  $t_{d(off)}$ ,  $t_f$ 

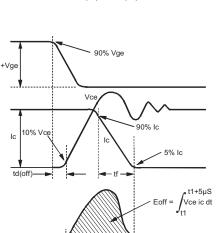


Fig. 18b - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{\text{off}},\,t_{\text{d(off)}},\,t_{\text{f}}$ 

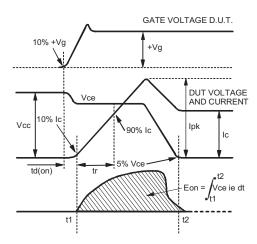


Fig. 18c - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{on}$ ,  $t_{d(on)}$ ,  $t_{r}$ 

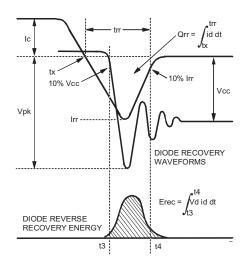


Fig. 18d - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{rec},\,t_{rr},\,Q_{rr},\,I_{rr}$ 

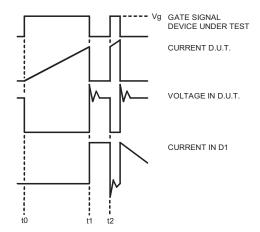
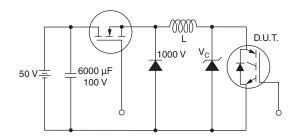


Fig. 18e - Macro Waveforms for Figure 18a's Test Circuit





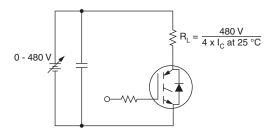
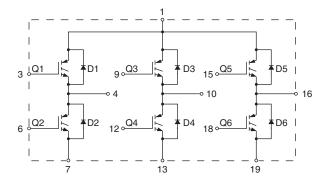


Fig. 19 - Clamped Inductive Load Test Circuit

Fig. 20 - Pulsed Collector Current Test Circuit

#### **CIRCUIT CONFIGURATION**

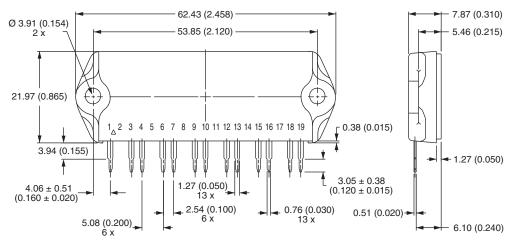


LINKS TO RELATED DOCUMENTS				
Dimensions	www.vishay.com/doc?95066			



# IMS-2 (SIP)

#### **DIMENSIONS** in millimeters (inches)



IMS-2 Package Outline (13 Pins)

#### Notes

- $^{(1)}$  Tolerance uless otherwise specified  $\pm$  0.254 mm (0.010")
- (2) Controlling dimension: inch
- (3) Terminal numbers are shown for reference only

Document Number: 95066 Revision: 30-Jul-07



### **Legal Disclaimer Notice**

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